



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

| APPLICATION NO. | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO. |
|-----------------|-------------|----------------------|---------------------|------------------|
|-----------------|-------------|----------------------|---------------------|------------------|

10/730,123

12/09/2003

Tatsuo Sengoku

009683-488

4345

21839

7590

12/09/2005

BUCHANAN INGERSOLL PC
(INCLUDING BURNS, DOANE, SWECKER & MATHIS)
POST OFFICE BOX 1404
ALEXANDRIA, VA 22313-1404

EXAMINER

PRUCHNIC, STANLEY J

ART UNIT

PAPER NUMBER

2859

DATE MAILED: 12/09/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

| | | | |
|------------------------------|---|---------------------------------------|--|
| Office Action Summary | Application No. 10/730,123 | Applicant(s) SENGOKU ET AL. | |
| | Examiner Stanley J. Pruchnic, Jr. | Art Unit 2859 | |

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 29 September 2005.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-15 is/are pending in the application.
- 4a) Of the above claim(s) 4-15 is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-3 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 09 December 2003 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

Priority

1. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Election/Restrictions

2. Applicant's election without traverse of Group I (Claims 1-3) in the reply filed on 13 December 2004 is acknowledged.

3. Claims 4-15 are withdrawn from further consideration pursuant to 37 CFR 1.142(b) as being drawn to a nonelected invention, there being no allowable generic or linking claim. Election was made without traverse in the reply filed on 13 December 2004.

4. Applicant is reminded that upon the cancellation of claims to a non-elected invention, the inventorship must be amended in compliance with 37 CFR 1.48(b) if one or more of the currently named inventors is no longer an inventor of at least one claim remaining in the application. Any amendment of inventorship must be accompanied by a request under 37 CFR 1.48(b) and by the fee required under 37 CFR 1.17(i).

Response to Arguments

5. Applicant's arguments with respect to claims 1-3 have been considered but are moot in view of the new ground(s) of rejection.

6. Applicant's arguments, see the Remarks, filed 29 September 2005, with respect to the rejection(s) of claim(s) 1-3 under 35 U.S.C. § 103(a) have been fully considered but are not persuasive as applied to the amended claim(s).

Applicant's description of Ebihara *et al.* (U. S. Patent No. 4,237,420, **EBIHARA**) in the REMARKS filed 29 September 2005 (page 9, lines 7-12ff) recognized that EBIHARA disclosed a monostable multivibrator ("TEMPERATURE SENSOR OSM", labeled 10 in Fig. 1, labeled 11 in Fig. 2) having a "time constant element" [R or C] responsive to temperature (see **EBIHARA**, Col. 2, Lines 52-58). It should also be noted

that the resistor 14 is not merely “adjustable”, but is “temperature dependent”: See also, for example, the notation in Figs. 2-3, wherein the “T” is recognized by one of ordinary skill in the art as indicating a temperature-dependent resistor, e.g., a thermistor. It is well known that the time constant of the OSM is determined by the product of the values of “R” and “C” of the respective resistor 14 and capacitor 16 “time constant elements”. The output pulse “b” has a duration, which duration is dependent on the product “RC” and the input threshold of the inverter 18, as explained by **EBIHARA** in Col. 2, Lines 47-52).

- a. Applicant's argument (First Paragraph on Page 10) that Ebihara *et al.* (U.S. Patent No. 4,237,420, **EBIHARA**) does not disclose a delay circuit connected to a signal output circuit is not persuasive, since the “signal output circuit” is identified as “start signal source 22” and “OSM 10/11” is a “delay circuit” as described above.
- b. Applicant's argument that **EBIHARA** does not disclose a pulse width measurement circuit directly receiving a signal from a logic circuit as claimed by Applicant in Claim 1 is not persuasive as applied to the amended claim(s), as is described in the new rejection, *infra*.
- c. Finally, regarding the argument(s) in the third Paragraph on Page 10 of the REMARKS: In response to applicant's arguments against the references individually, one cannot show nonobviousness by attacking references individually where the rejections are based on combinations of references. See *In re Keller*, 642 F.2d 413, 208 USPQ 871 (CCPA 1981); *In re Merck & Co.*, 800 F.2d 1091, 231 USPQ 375 (Fed. Cir. 1986). The Office Action already acknowledged that said pulse width measurement circuit (**23**) of **EBIHARA** lacked an integration circuit receiving a signal output from said logic circuit and a Schmitt trigger circuit receiving a signal output from said integration circuit, said Schmitt trigger circuit having a trigger potential set to have a value corresponding to said predetermined width, as claimed by applicant in Claim 1. The secondary reference MEHNERT is provided as evidence of the art recognized equivalence of the two types of pulse width discrimination, as described *infra*.

Claim Rejections - 35 USC § 103

7. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

8. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

9. Claims 1-3 are FINALLY rejected under 35 U.S.C. 103(a) as being unpatentable over Ebihara *et al.* (U. S. Patent No. 4,237,420, hereinafter **EBIHARA**) in view of **MEHNERT** (U. S. Patent No. 4,873,518 A) and JP7/326714 (hereinafter **NISHIGAKI**).

Regarding Claim 1, **EBIHARA** discloses a temperature detection circuit (Fig. 1) including:

a signal output circuit (**22**) outputting a first signal (**a**) having at least one rising or falling portion;

a delay circuit (**including elements of "OSM" 10 labeled 14, 16 and 18; Fig. 1**) connected to (connected indirectly by means of NOR gate 12) the signal output circuit 22 and formed of at least one inverter (**18**) to output a delayed version (**b**) of said first signal;

a logic circuit (**the "OSM" 10, including NOR gate 12**) receiving said first signal (**a**) and said delayed version (**b**) of said first signal;

a pulse width measurement circuit (**23**) outputting

a signal asserted (Rx) in response to
a signal directly received (b) from said logic circuit 10
having a pulse with a width of no less than a predetermined
width corresponding to a temperature desired to be detected; and
a latch circuit (counter 26) latching a signal output from said pulse width
measurement circuit.

EBIHARA as described above, does not disclose said pulse width
measurement circuit (23) having

an integration circuit receiving a signal output from said logic circuit
and
a Schmitt trigger circuit receiving a signal output from said
integration circuit, said Schmitt trigger circuit having a trigger potential set
to have a value corresponding to said predetermined width,
as claimed by applicant in Claim 1.

Although EBIHARA discloses an integration circuit (capacitor 16;
resistor 14) receiving a signal (a NOR b) output from said logic circuit (“OSM”
10). The circuit including inverter (18) functions as described by EBIHARA in
Col. 2, Lines 28-66: One or both of Resistor 14 and Capacitor 16 varies linearly
with temperature (Col. 2, Lines 47-56). The input threshold of inverter 18, in
combination with the integration circuit temperature dependence, results in the
output pulse “b” having a width related to temperature, as described by
EBIHARA.

EBIHARA further discloses the pulse width measurement circuit 23
including a source 28 of clock pulses Cx combined with the output pulse “b” at
the AND gate 24 so that counter 26 will count clock pulses while the AND gate is
enabled by the pulse “b”, thus measuring the width of the temperature-dependent
pulse width.

To summarize, **EBIHARA** as described above, disclosed the invention as claimed by Applicant, but EBIHARA does not disclose said pulse width measurement circuit (23) having

an integration circuit receiving a signal output from said logic circuit
and

a Schmitt trigger circuit receiving a signal output from said
integration circuit, said Schmitt trigger circuit having a trigger potential set
to have a value corresponding to said predetermined width,
as claimed by applicant in Claim 1.

MEHNERT discloses embodiments of a pulse width measurement (discrimination) circuit 20 (Fig. 1) that is evidence of the art recognized equivalence (Col. 9, Lines 58-65) of a purely digital form (Fig. 2) including a counter and (as shown in Fig. 3) an analog/digital form including an "RC-member 60" (Col. 9, Lines 58-68), which is an integrating circuit as claimed by Applicant in Claim 1, and MEHNERT further discloses a Schmitt trigger circuit (**70**) receiving a signal output from said integration circuit 60, said Schmitt trigger circuit having a trigger potential set to have a value corresponding to said predetermined width (Col. 10, Lines 27-35), the width being set by the selected values of resistor 66 and capacitor 67 (e.g., for "RC-member 60", the width being 90 microseconds).

Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to substitute a pulse width measurement circuit, as taught by **MEHNERT**, including an integration circuit receiving the signal "b" output from said logic circuit 18 and a Schmitt trigger circuit receiving a signal output from said integration circuit, said Schmitt trigger circuit having a trigger potential set to have a value corresponding to said predetermined width (predetermined by the integration circuit) for the pulse width measurement circuit of **EBIHARA**, including the counter, in order to perform the same function as the width pulse measurement circuit 23 of EBIHARA, since they are art recognized equivalents used for measuring pulse width as

taught by **MEHNERT** and the use of the RC integrator circuit would allow the output to be adjusted for a desired temperature.

EBIHARA as described above, does not explicitly disclose said circuit is a semiconductor integrated circuit as claimed by applicant in Claim 1. **EBIHARA** as described above, does not claim the components located on semiconductor integrated circuits as claimed by Applicant in claims 2-3.

NISHIGAKI discloses components on separate semiconductor integrated circuits, e.g., the buffer circuit (inverter) 50 is located on a CPU in order to detect that chip's internal temperature. Moreover, it is well known in the art of temperature sensing that the pulse width measurement circuit would be affected by temperature changes.

Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to shift the positions of these components, in order to keep the pulse width measurement circuit away from the hottest areas so it will have more accurate results, and based on the intended use for the temperature dependent oscillator to measure the temperature of the CPU chip as taught by **NISHIGAKI**.

Conclusion

10. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire **THREE MONTHS** from the mailing date of this action. In the event a first reply is filed within **TWO MONTHS** of the mailing date of this final action and the advisory action is not mailed until after the end of the **THREE-MONTH** shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than **SIX MONTHS** from the date of this final action.

Art Unit: 2859

11. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Stanley J. Pruchnic, Jr., whose telephone number is **(571) 272-2248**. The examiner can normally be reached on weekdays (Monday through Friday), the best hours being from 8:30 AM to 4:00 PM. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Diego Gutierrez (Art Unit 2859) can be reached at **(571) 272-2245**. The Central FAX Number for all official USPTO communications is **571-273-8300**.

Any inquiry of a general nature or relating to the status of this application or proceeding may be directed to the official USPTO website at <http://www.uspto.gov/> or you may call the **USPTO Call Center** at **800-786-9199** or 703-308-4357. The Technology Center 2800 Customer Service FAX phone number is (703) 872-9317.

The cited U.S. patents and patent application publications are available for download via the Office's PAIR. As an alternate source, all U.S. patents and patent application publications are available on the USPTO web site (www.uspto.gov), from the Office of Public Records and from commercial sources.

Private PAIR provides external customers Internet-based access to patent application status and history information as well as the ability to view the scanned images of each customer's own application file folder(s).

For inquiries relating to Patent e-business products and service applications, you may call the *Patent Electronic Business Center (EBC)* at 703-305-3028 or toll free at 866-217-9197 between the hours of 6 a.m. and midnight Monday through Friday EST, or by e-mail at: ebc@uspto.gov. Additional information is available on the Patent EBC Web site at: <http://www.uspto.gov/ebc/index.html>.



**DIEGO F. F. GUTIERREZ
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 2800**



Stanley J. Pruchnic, Jr.
12/7/05